



BSI Standards Publication

Measurement of quartz crystal unit parameters

Part 8: Test fixture for surface mounted quartz crystal units

National foreword

This British Standard is the UK implementation of EN 60444-8:2017. It is identical to IEC 60444-8:2016. It supersedes BS EN 60444-8:2003, which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee EPL/49, Piezoelectric devices for frequency control and selection.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Amendments/corrigenda issued since publication

Date	Text affected
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English Version

**Measurement of quartz crystal unit parameters -
Part 8 : Test fixture for surface mounted quartz crystal units
(IEC 60444-8:2016)**

Mesure des paramètres des résonateurs à quartz -
Partie 8: Dispositif d'essai pour les résonateurs
à quartz montés en surface
(IEC 60444-8:2016)

Messung von Schwingquarz-Parametern -
Teil 8: Prüfaufbau für oberflächenmontierbare
Schwingquarze
(IEC 60444-8:2016)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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European foreword

The text of document 49/1126/CDV, future edition 2 of IEC 60444-8, prepared by IEC/TC 49 "Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60444-8:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2017-10-19
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-01-19

This document supersedes EN 60444-8:2003.

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The text of the International Standard IEC 60444-8:2016 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60122-1	NOTE	Harmonized as EN 60122-1.
IEC 60444-1:1986	NOTE	Harmonized as EN 60444-1:1997 (not modified).
IEC 60444-2	NOTE	Harmonized as EN 60444-2.
IEC 60444-6	NOTE	Harmonized as EN 60444-6.
IEC 60444-7	NOTE	Harmonized as EN 60444-7.
IEC 60444-9	NOTE	Harmonized as EN 60444-9.
IEC 61837-1	NOTE	Harmonized as EN 61837-1.
IEC 61837-2	NOTE	Harmonized as EN 61837-2.
IEC 61837-3	NOTE	Harmonized as EN 61837-3.
IEC 61837	NOTE	Harmonized in EN 61837 series.

Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60444-5	-	Measurement of quartz crystal unit parameters - Part 5: Methods for the determination of equivalent electrical parameters using automatic network analyzer techniques and error correction	EN 60444-5	-

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